Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/632,665	HAPARNAS ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	

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Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	7/5/2006	S.C.		
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